

beam (6) and the reflected light (15) can be electronically evaluated and that the frequency shift ( $v-v'$ ) of the reflected light (15) can be determined therefrom.

A1  
corr.

6. (amended) A device as claimed in claim 1, characterized in that the speed of rotation ( $v$ ) of a rotating defect (14) can be calculated from the frequency shift ( $v-v'$ ) by way of the Doppler formula.

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A2

8. (amended) A device as claimed in claim 1, characterized in that the moving surface (8) is associated with a device for detecting its instantaneous orientation.

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A3

10. (amended) A device as claimed in claim 4, characterized in that the position of a defect (14) on the inspected surface relative to said scale can be determined from the signal detected by the detector (16; 17).

11. (amended) A device as claimed in claim 1, characterized in that the surface (8) to be inspected can move in a rotational as well as in a translational mode.

12. (amended) A device as claimed in claim 1, characterized in that the light beam (2) that is emitted by the light source (1) is